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<b>Combined Form PTO/SB/08A&amp;B</b>  <b><u>INFORMATION DISCLOSURE</u></b> <b><u>STATEMENT BY APPLICANT</u></b>  <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	New Application
				Confirmation Number	
				Filing Date	February 6, 2006
				First Named Inventor	Hideki NINOMIYA et al.
				Art Unit	
Examiner Name		Attorney Docket Number	062088		
Sheet	1	of	1		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>3</sup> (if known)		
/LGL/	1	US 4,573,792		03-04-1986	Koichi KAJIYAMA et al.
/LGL/	2	US 2002/0118352		08-29-2002	Akira OHZU et al.
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Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
	3	JP	49-100997		09-24-1974	Noumi Disaster Prevention Mfg. Co., Ltd.	Abstract, cited in the ISR
/LGL/	4	JP	59-10835		01-20-1984	Komatsu Ltd.	Abstract, cited in the ISR
/LGL/	5	JP	6-288858		10-18-1994	Osaka Gas Co., Ltd.	Abstract, cited in the ISR
/LGL/	6	JP	9-178566		07-11-1997	Tokai Carbon Co., Ltd.	Abstract, cited in the ISR

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
/LGL/	7	W. A. de GROOT; "The Use of Spontaneous Raman Scattering for Hydrogen Leak Detection" 30 <sup>th</sup> AIAA/ASME/SAE/ASEE Joint Propulsion Conference, June 27-29, 1994, pp.1-11. Cited in the International Search Report.	
/LGL/	8	International Search Report, dated July 27, 2004 of PCT/JP2004/008038	

Examiner Signature	/Layla G. Lauchman/	Date Considered	09/11/2008
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